Se	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/646,696	LIN ET AL.	
Examiner	Art Unit	
Alicia M. Lewis	2164	

	SEAR	CHED	
Class	Subclass	Date	Examiner
7/6	1,4	1/4/08	.9C
707	100		
	601		
	104/	V	7

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
707	100	1/24 8	51
	104/		
7/6	1,4	$\downarrow$	V
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(INCLUDING SEAF	CH STRATE	GY)
	DATE	EXMR
EAST keyword	2/6/200	6 AL